SHIGA7.036APC PATENT

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

OK TO ENTER: /JSC/

03/15/2008

Applicant : Masuda et al.

: 10/564,510 Appl. No.

Filed : January 12, 2006

For : POSITIVE PHOTORESIST

COMPOSITION AND METHOD

OF FORMING RESIST PATTERN

: Chu, John S Y Examiner

Group Art Unit : 1752

## RESPONSE TO OFFICE ACTION

## Mail Stop Amendment Commissioner for Patents

P.O. Box 1450 Alexandria, VA 22313-1450

## Dear Sir:

In response to the Office Action mailed December 12, 2007, please amend the abovereferenced application as follows:

A listing of claims begins on page 2 of this paper for the Examiner's convenience. No amendments have been made

Remarks/Arguments begin on page 5 of this paper.